

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination CHIN ET AL.	
		Examiner Chen-Wen Jiang	Art Unit 3744	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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	N	JP 07027426 A	01-1995	Japan	NOGUCHI et al.	
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